

SEM (Scanning Electron Microscope)



Scanning electron microscopy is based on the use of electrons which are emitted from field emission gun (FEG) to exploit interactions on the sample surface. SEM image depends on the principle of collecting and examining the signals generated by the physical interaction of the electron beam with the surface of the sample being examined.

Applications:

- Conductive/Insulator materials
- Biological materials
- Geological samples
- Textiles

Instrument Model: Thermo Scientific Apreo S LoVac

Instrument Hardware and Features:

Detectors: ETD (SE) , T1 (In-Column BSE) - T2 (In-Column SE), Retractable BSE, EBIC, STEM, LVD, EDS

Sample chamber inner diameter: 340 mm

Vacuum: High- vacuum – Low vacuum

Electron Source: Schottky Field Emission Gun (FEG)